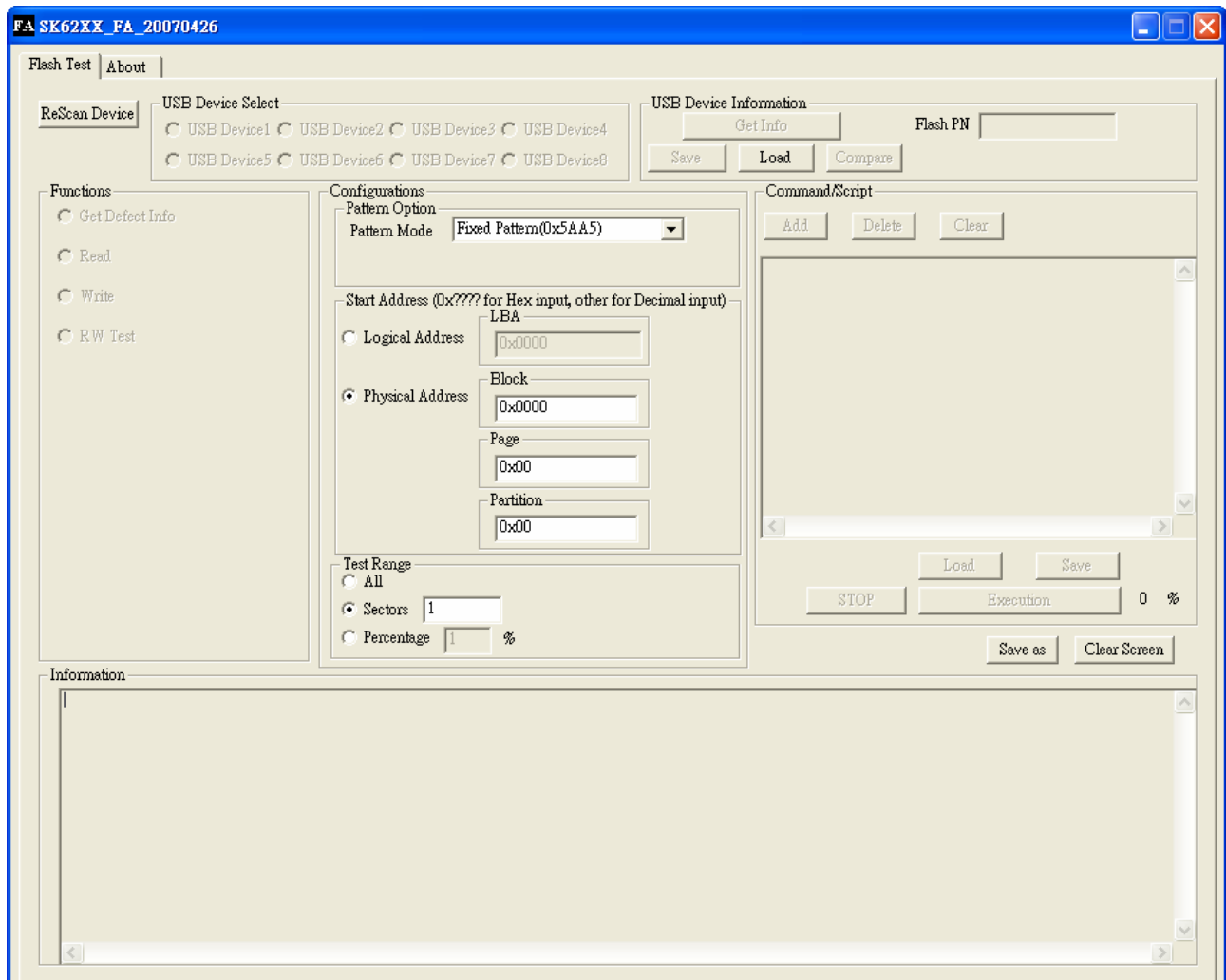


1. Screen Layout



- ☒ Purpose of Two-Page architecture:
 - ☐ “Flash Test” Page:
 - conductive execution flow,
 - display device info,
 - compare device info with Golden,
 - selectable test item,
 - setup configuration of each test item,
 - review configuration of each test item,
 - display analysis result of each test item,
 - ☐ “About” Page:
 - None(Tentative),
- ☒ Elements of “Flash Test” Page:
 - ☐ Rescan Device button to check front end.
 - ☐ USB device radio button to select the analysis device.
 - ☐ Get Info button to get the device info.
 - ☐ Save button to save the device info by file/directory.
 - ☐ Load button to load the device info.
 - ☐ Compare button to compare the loaded and current device info.
 - ☐ Flash PN window to display flash part number of current device.
 - ☐ Get Defect Info radio button to select get device system and defect block info function.
 - ☐ Read radio button to select read function.

- ☐ Write radio button to select write function.
- ☐ RW Test radio button to select WRC function.
- ☐ Pattern Mode to select test pattern.
- ☐ Logical Address radio button to select test in LBA.
- ☐ Physical Address radio button to select test in Physical address.
- ☐ LBA Edit box to edit test start LBA.
- ☐ Block Edit box to edit test start Block.
- ☐ Page Edit box to edit test start Page.
- ☐ Partition Edit box to edit test start Partition.
- ☐ All radio button to select test range as all device.
- ☐ Sectors to select test range as sectors.
- ☐ Percentage to select test range as the percentage of all device.
- ☐ Command/Script window to show the test items to be executed.
- ☐ Add button to add test item into the command window.
- ☐ Delete button to delete test item of the command window.
- ☐ Clear button to clear all test items of the command window.
- ☐ Load button to load test item into the command window.
- ☐ Save button to save all test items of the command window by file/directory..
- ☐ Execution button to execute the test items in the command window.
- ☐ STOP button to stop the execution.
- ☐ Information window to display the device info and analysis info.
- ☐ Save as to save FA analysis result by file/directory.
- ☐ Clear Screen to clear the Information window.

☒ Elements of "About" Page:

- ☐ None

2. User Flow

2.1 Scan UFD

- ☐ Press Rescan Device button to check all connected device and Front End test will be done.
- ☐ Select the test device by click the USB device radio button.
- ☐ Select the device flash part number

2.2 Get Device Information

- ☐ Press Get Info button to get the device info which will be displayed on Information window.
- ☐ User can save the device info by press Save button.
- ☐ User can load the device info by press Load button.
- ☐ User can compare the loaded and current the device info by press Compare button.

2.3 NAND Analysis

- ☐ Click the test radio button in the Functions Group Box to select the test item.
- ☐ Select the Pattern Mode in the Pattern Option Group Box if necessary.
- ☐ Click the Logical Address or Physical Address radio button and edit the LBA or Block/Page/Partition box to set the test start address.
- ☐ Click the All or Sectors or Percentage radio button and edit the box to set the test range.
- ☐ Press Add button to add the test item and configuration into the Command/Script window.
- ☐ Press Execution button to run the test.
- ☐ User can press STOP button to stop the testing.
- ☐ User can also add or delete other test items into the Command/Script window by pressing Add or Delete button.

- ❑ User can load or save the Command/Script window by pressing Load or Save button.
- ❑ User can save or clear the Information window by pressing Save as or Clear Screen button.